



PCN# : P69DAAB Issue Date : Nov. 09, 2016

DESIGN/PROCESS CHANGE NOTIFICATION

This is to inform you that a change is being made to the products listed below.

Unless otherwise indicated in the details of this notification, the identified change will have no impact on product quality, reliability, electrical, visual or mechanical performance and affected products will remain fully compliant to all published specifications. Products incorporating this change may be shipped interchangeably with existing unchanged products.

This change is planned to take effect in 90 calendar days from the date of this notification. Please work with your local ON Sales Representative to manage your inventory of unchanged product if your evaluation of this change will require more than 90 calendar days.

Please contact your local Customer Quality Engineer within 30 days of receipt of this notification if you require any additional data or samples.

Implementation of change:

Expected First Shipment Date for Changed Product : Feb. 07, 2017

Expected First Date Code of Changed Product :1707

Description of Change (From) : Bump Site : Amkor, Taiwan Test to DPS : Amkor, Taiwan

Description of Change (To) : Bump Site: Amkor and ASE, Taiwan Test to DPS : Amkor, Taiwan and ON Semiconductor Cebu Philippines

Reason for Change:

Adding ASE, Taiwan and ON Semiconductor Cebu, Philippines as alternate Bump and Test/DPS Sites.

- Improved supply flexibility.

- Better quality and yields through equipment and facility upgrades.



Affected Product(s):

FPF12045UCX	FPF1204BUCX	FPF1204UCX

FPF1204UCX – Maine / ASE/Cebu package qualification data: PCN# P69DAAB

Qualification Plan	Device	Package	Process	No. of Lots
Q20160375	FPF1204UCX	UCBBU-A04	Maine FS35C52B	3
			-ASE bump /Cebu DPS	

Test Description:	Condition:	Standard :	Duration:	Results:
Highly Accelerated Stress Test	130C, 85%RH, 5.5V	JESD22-A110	96 hrs	0/231
Unbiased Highly Accelerated Stress Test	130C, 85%RH,	JESD22-A118	96 hrs	0/231
Temperature Cycle	-40C, 125C	JESD22-A104	850 Cycles	0/231

ON Semiconductor®



Title : Qualification Report for PCN : P69DAAB

Date : Nov. 08, 2016

Affected devices :

С			
Product	Customer Part NumberB	BBB	Drawing
FPF1204UCX	Y	/	N

Qualification Test Summary :

FPF1204UCX - Maine / ASE/Cebu package qualification data: PCN# P69DAAB

Qualification Plan	Device	Package	Process	No. of Lots
Q20160375	FPF1204UCX	UCBBU-A04	Maine FS35C52B	3
			-ASE bump /Cebu DPS	

Test Description:	Condition:	Standard :	Duration:	Results:
Highly Accelerated Stress Test	130C, 85%RH, 5.5V	JESD22-A110	96 hrs	0/231
Unbiased Highly Accelerated Stress Test	130C, 85%RH,	JESD22-A118	96 hrs	0/231
Temperature Cycle	-40C, 125C	JESD22-A104	850 Cycles	0/231

The selection methodology of qualification vehicles is aligned with JESD47 and if automotive devices are impacted by the PCN the selection of qualification vehicles is also align with the requirements in AEC-Q100 or AEC-Q101

Please contact your local Customer Quality Engineer if you have any questions concerning this data.